

Marking permanency test method

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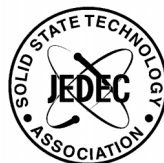
IEC/PAS 62175:2000

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PUBLICLY AVAILABLE SPECIFICATION



INTERNATIONAL
ELECTROTECHNICAL
COMMISSION



Reference number
IEC/PAS 62175

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EIA/JESD22-B107-A

EIA/JEDEC STANDARD

Test Method B107-A

Marking Permanency

EIA/JESD22-B107-A

(Revision of Test Method B107 - previously published in JESD22-B)

SEPTEMBER 1995

ELECTRONIC INDUSTRIES ASSOCIATION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

MARKING PERMANENCY TEST METHOD

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IEC-PAS 62175 was submitted by JEDEC and has been processed by IEC technical committee 47: Semiconductor devices.

The text of this PAS is based on the following document:

This PAS was approved for publication by the P-members of the committee concerned as indicated in the following document:

Draft PAS	Report on voting
47/1448/PAS	47/1481/RVD

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